Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/083,280	SUGAYA, SHIG	ERU
Examiner	Art Unit	
Thien D. Tran	2665	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPAT, USPAT, USOCR, EPO, DERWENT). 370/229, 230, 349.	11/27/2005	тт		
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